

**Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)**

Contribution ID : 0

Type : **not specified**

Opening of the Workshop and Introduction of the participants

Monday, 26 September 2016 08:30 (1:00)

Content

Summary

Session Classification : DAY 1